

Appl. No. 10/709,502
Amdt. dated April 17, 2006
Reply to Office action of February 02, 2006

Amendments to the Claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

- 5 Claim 1 (currently amended): A method for generating a command file of a group of design rule check (DRC) rules for being used by a layout verification tool to verify the a design of an integrated circuit, the method comprising:
- (a) selecting a process from a group of processes;
 - (b) setting a set of parameters; and
 - 10 (c) extracting program codes from a plurality of modules according to the selected process and the set of parameters so as to generate; and
 - (d) combining the program codes extracted from the plurality of modules to form a corresponding command file of the group of DRC rules to be run by the layout verification tool to verify the design of the integrated circuit.
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- Claim 2 (currently amended): The method of claim 1 further comprising:
- [[(d)]] (e) generating the plurality of modules, the plurality of modules comprising:
 - a header module comprising program codes for settings of a verification tool of different processes;
 - 20 a variable module comprising program codes for setting fabrication parameters of different processes;

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a layer module comprising program codes for setting layer definitions of
different processes; and

an operation module comprising program codes of operation definitions of
different processes.

- 5 Claim 3 (currently amended): The method of claim 1 wherein the set of parameters
~~emprise~~ comprises number of metal layers.

Claim 4 (currently amended): The method of claim 1 wherein the set of parameters
~~emprise~~ comprises number of poly-silicon layers.

- 10 Claim 5 (currently amended): The method of claim 1 wherein the set of parameters
~~emprise~~ comprises package parameters.

Claim 6 (currently amended): A method for generating a command file of a group of
layout versus schematic (LVS) rules and layout parasitic extraction (LPE) rules to be
used by a layout verification tool to verify the a layout and the parasitic
characteristics of an integrated circuit, the method comprising:

- 15 (a) selecting a process from a group of processes;
(b) setting a set of parameters; and
(c) extracting program codes from a plurality of modules according to the selected
process and the set of parameters ~~so as to generate ; and~~
(d) combining the program codes extracted from the plurality of modules to form a
20 corresponding command file of the group of LVS/LPE rules to be run by the
layout verification tool to verify the layout and parasitic characteristics of the
integrated circuit.

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Claim 7 (currently amended): The method of claim 6 further comprising:

[[(d)]] (e) generating a plurality of modules, the plurality of modules comprising:

- 5 a header module comprising program codes for settings of a verification tool of different processes;
- a layer module comprising program codes for setting layer definitions of different processes;
- an operation module comprising program codes of operation definitions of different processes; and
- 10 a device module comprising program codes for declaring devices of different processes.

Claim 8 (currently amended): The method of claim 6 wherein the set of parameters ~~comprise~~ comprises number of metal layers.

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Claim 9 (currently amended): The method of claim 6 wherein the set of parameters ~~comprise~~ comprises number of poly-silicon layers.

Claim 10 (currently amended): The method of claim 6 wherein the set of parameters ~~comprise~~ comprises package parameters.

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- Claim 11 (currently amended): A method for generating a command file of a group of design rule check (DRC) rules or layout versus schematic (LVS) rules and layout parasitic extraction (LPE) rules to be used by a layout verification tool to verify the a layout and the parasitic characteristics of an integrated circuit, the method comprising:
- 5 (a) choosing whether to generate a command file of DRC rules or a command file of LVS/LPE rules;
- (b) selecting a process from a group of processes;
- 10 (c) setting a set of parameters; and
- (d) extracting program codes from a plurality of modules according to the choice in step [(k)] (a), the selected process, and the set of parameters so as to generate a ; and
- 15 (e) combining the program codes extracted from a plurality of modules to form the command file of DRC rules or the command file of LVS/LPE rules to be run by the layout verification tool.

Claim 12 (currently amended): The method of claim 11 further comprising:

- [(e)] (f) generating a plurality of modules, the plurality of modules comprising:
- 20 a header module comprising program codes for settings of a verification tool of different processes;
- a variable module comprising program codes for setting fabrication parameters of different processes;

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a layer module comprising program codes for setting layer definitions of
different processes;

an operation module comprising program codes of operation definitions of
different processes; and

5 a device module comprising program codes for declaring devices of different
processes[[:]] .

Claim 13 (currently amended): The method of claim 11 wherein the set of parameters
~~comprise~~ comprises number of metal layers.

10 Claim 14 (currently amended): The method of claim 11 wherein the set of parameters
~~comprise~~ comprises number of poly-silicon layers.

Claim 15 (currently amended): The method of claim 11 wherein the set of parameters
~~comprise~~ comprises package parameters.